



**INTERNATIONAL
TEST CONFERENCE**
Oct. 23 – Oct. 25, 2007
Santa Clara Convention Center
Santa Clara, CA, USA

The Cornerstone of Test Week™
Test Week: Oct. 21 – Oct. 26, 2007

CALL FOR PARTICIPATION Corporate Presentations

Corporate Presentations

International Test Conference is the world's premier conference dedicated to the electronic test of devices, boards and systems-covering the complete cycle from design verification, test, diagnosis, and failure analysis, back to process and design for yield improvement.

ITC is offering conference exhibitors and prime corporate supporters (diamond, platinum, gold, and silver) the opportunity to give technical presentations in a track parallel to the technical sessions. These presentations will be listed in the conference program along with the technical sessions, and should be targeted to the ITC technical audience. The corporate presentation sessions will differ from standard ITC presentations in that product names and logos may be mentioned explicitly. Typical content could include product descriptions, case studies, best practices, and testimonials.

Presentation opportunities are only available to registered ITC exhibitors and corporate supporters. Space will be allocated on a first-come, first-served basis, with one 30-minute time slot per 20-minute presentation. Attendance at the sessions will be open to all conference and exhibit attendees. Company representatives will be free to hand out literature at the session.

Proposals should be in summary form (see below) and will be reviewed for content by the ITC program committee in order to ensure high quality. Submissions must include:

- Title of presentation.
- Name, affiliation, mailing address, e-mail address, phone and fax number of each author.
- Designation of the presenter(s). ITC will communicate with the presenter(s).
- An abstract of 25 words or less to be included in the Advance Program and Conference Guide.

Please note that all deadlines are firm.

*Submission Deadline: **August 1, 2007***

*Initial Presentation Deadline and Final Title and Abstract Deadline: **August 25, 2007***

*Final Presentation Deadline: **September 15, 2007***

All submissions and presentations must be in electronic format. Prospective authors should read the detailed instructions regarding formats and submission requirements that are available on the ITC Web site at: <http://www.itctestweek.org>

For further information, check the ITC Web page or contact:

International Test Conference,
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Corporate Presentation Chair:

Erik Volkerink
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Conference Theme:

This year ITC will focus on refined as well as breakthrough test technologies for nanometer-technology designs. What innovative test methods are you working on that will fundamentally address the nanometer-technology challenges such as quality and cost of test?

Conference Focus Topics:

Adaptive Test
BIST or Embedded Test-Chip and Board
Bring-up Test and Debug
Design and Test for Reliability
Experiments and Case Studies
High-Speed I/O Test
High-Speed Digital Test
Low-Cost Test/ATE
On-Chip Test Compression
RF Testing
Test Data Analysis
Test and Design for Manufacturability
Test for Nanometer Technologies
Test Resource Partitioning

Hot Topics:

Board and System Test
Defect-based Testing
Innovative Industrial Test Practices
On-line Test
Power Issues in Test
Volume Diagnosis and Yield Learning

General Chair:

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Exhibits Vice Chair:

Ron Press
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